

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No. 10/539,247 Conf. No. 9258  
In Re Application of: Gattiker *et al.* Art Unit: 2829  
Filed: 06/16/2005 Dkt. #: BUR920020068US1 (IBMF-0010)  
Examiner: Nguyen, Vinh P.

Title: **INTEGRATED CIRCUIT TESTING METHODS USING WELL BIAS MODIFICATION**

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT**

Sir:

**I. INTRODUCTORY COMMENTS**

Please reconsider the above-identified application in light of the following amendments and remarks.

**The Claims** are reflected in the listing of claims that begin on page 2 of this paper.

**Remarks** begin on page 9 of this paper.